

Fig. 1

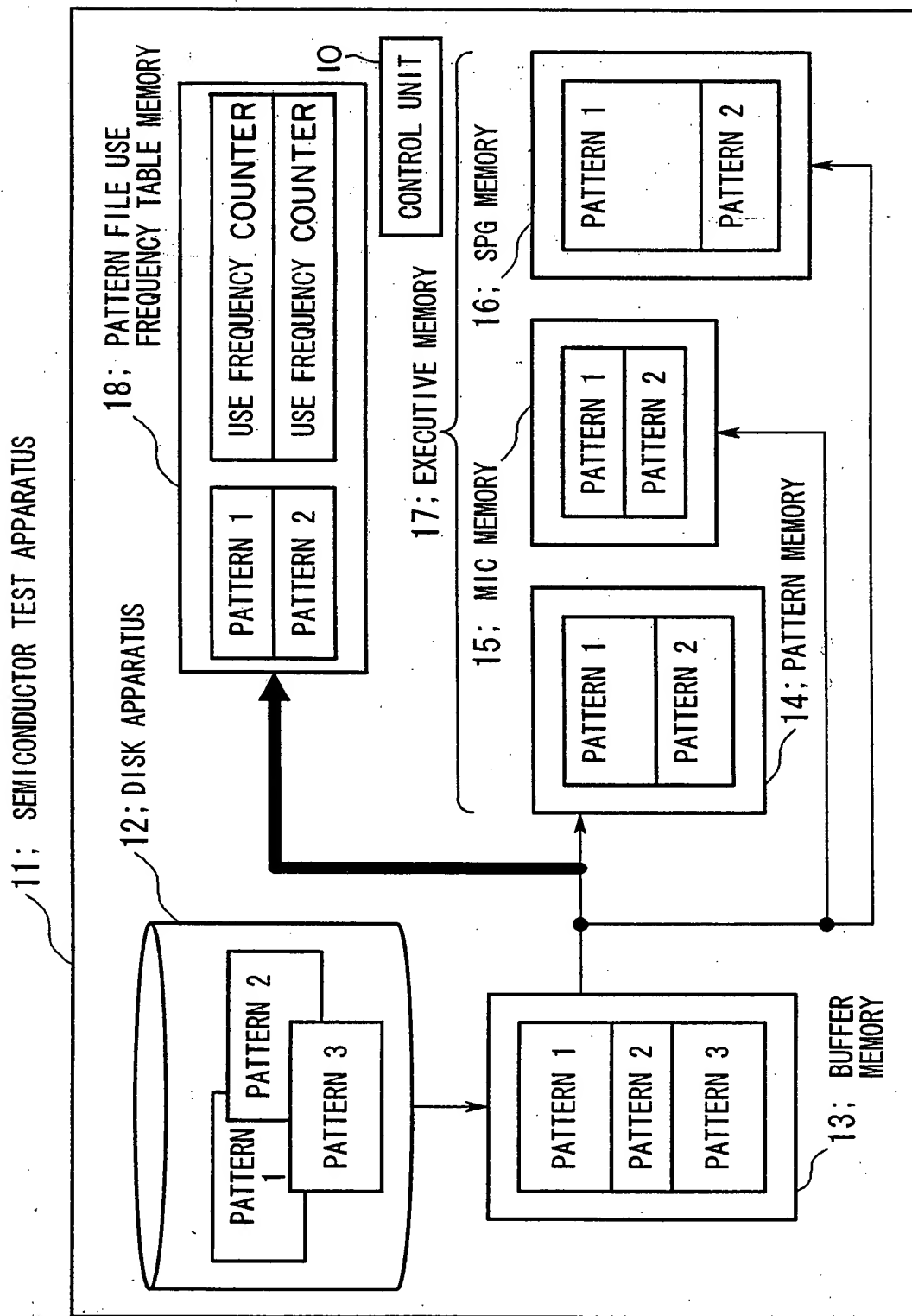


Fig. 4 (PRIOR ART)

41; SEMICONDUCTOR TEST APPARATUS

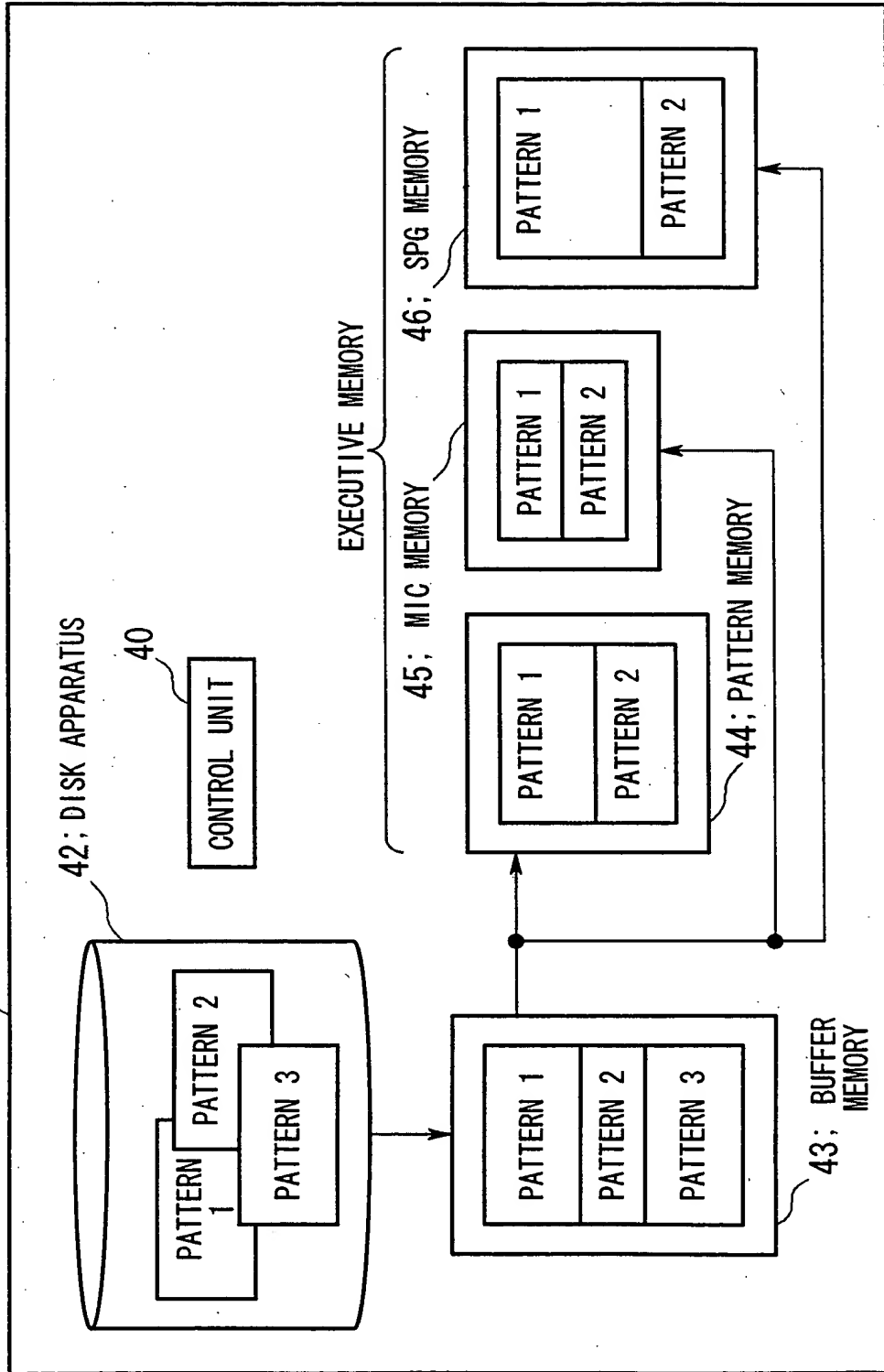




Fig.5
(PRIOR ART)

